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X-RAY INSTRUMENTATION



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RECAP OF THE PRINCIPAL OF THE SOURCE





SCHEMATIC OF A SYNCHROTRON RADIATION (SR) LIGHT SOURCE



A TYPICAL BEAMLINE LAYOUT



X-RAY BEAMS AT 3RD GENERATION SR SOURCES

- Beam size
 - Unfocused: few mm to few cm (source is weakly divergent)
 - Focused beam: < 100 nm to ~10's μm
- Energy range/tunability
 - 0.1eV < E < 0.5 MeV but mostly 3-100 keV
- Energy bandwidth (ΔE/E):
 - 10^{-2} to 10^{-8} at sample, typically $\Delta E \sim \text{few eV} @ 20 \text{keV}$
- Polarized radiation
 - 100% linear or circular or elliptical
- Pulsed radiation
 - 50 ps pulses every ns
- Power
 - several kW total power, several 100 W/mm² power density (white beam)
- High degree of coherence
- Photon Flux
 - Brilliance: 10^{22} ph/sec/mrad²/mm² (10^{11} higher than conventional sources) \Rightarrow photon flux (@ $\Delta E/E = 10^{-4}$): $10^{9}-10^{14}$ ph/s
 - Extremely variable photon rates on detectors (< 1 ph/s to full beam flux)

WHAT DO WE MEAN BY X-RAY INSTRUMENTATION AT A SR SOURCE?



A TYPICAL EXPERIMENT



DETECTOR - SAMPLE 'ENVIRONMENT'

experiments are built around the samples to be measured

 \Rightarrow importance of sample environment (temperature; pressure; <u>E</u> and <u>B</u> fields...) need to physically manipulate sample during measurements (position, rotation...)



rapid turnover of samples and experiments

sample(s) in beam for minutes to hours experiments typically last a few days

Courtesy: John Morse

DIVERSITY OF APPLICATIONS \Rightarrow WIDE RANGE OF INSTRUMENTATION

The ESRF groups its 40+ beamlines according to scientific application:



Central Building

A COMPLETE SUITE OF TECHNIQUES

X-Ray Fluorescence

- Composition
- Quantification
- Trace element mapping

Specific Sample environments

Phase contrast X-ray imaging

- 2D/3D Morphology
- High resolution
- Density mapping

Infrared FTIR-spectroscopy

- Molecular groups & structure
- High S/N for spectroscopy
- Functional group mapping

X-ray Diffraction & scattering

- Long range structure
- Crystal orientation mapping
- Stress/strain/texture mapping

X-ray spectroscopy

- Short range structure
- Electronic structure
- Oxidation/speciation mapping



X-RAY INSTRUMENTATION: RÖNTGEN'S ORIGINAL WORK (1895)



after W.C. Röntgen Über eine neue art von Strahlen. Phys.-Med. Ges., Würzburg, <u>137</u>, (1895) English translation in Nature <u>53</u>, (1996)





• "... The refractive index.... cannot be more than 1.05 at most.... X-rays cannot be concentrated by lenses...."

"... Photographic plates and film are "susceptible to x-rays", providing a valuable means of recording the effects..."

• "... Detection of interference phenomena has been tried without success, perhaps only because of their feeble intensity..."





VISIBLE LIGHT OPTICS



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X-RAY OPTICS



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SILICON OPTICS – X-RAY MIRRORS





ESRF





ESRF NANOFOCUSING 'KIRKPATRICK-BAEZ' MIRROR SYSTEM



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PROJECTION MICROSCOPY USING KB OPTICS



SILICON OPTICS -MONOCHROMATORS





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COMPOUND REFRACTIVE LENSES





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A. Snigirev et al. Nature, <u>384</u> (1996)

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COMPOUND REFRACTIVE LENSES

LIGA-process





• Polymers (SU-8)

<u>Nickel</u>

V. Nazmov & V. Saile Microstructure Technology (IMT) FZK, Germany V. Nazmov *et al.*, NIM A 582 (2007)

Reactive ion etching (RIE)



<u>Silicon</u> C. G. Schroer, Institut für Strukturphysik Dresden, Germany C. G. Schroer *et al.*, APL <u>87</u> (2005)



Diamond C. David PSI, Villigen, Switzerland B. Nöhammer et al. JSR <u>10</u> (2003) The European Synchrotron

COMPOUND REFRACTIVE LENSES





diamond lenses

- high lens shape precision
- improved deepness of structures (but still not deep enough)
- still a problem: roughness
- successfully tested in an experiment at the ESRF



3136 Silicon NFLs on wafer about 600000 single lenses







WHY LONG BEAMLINES?





D=150-180m



PROGRESS IN HARD X-RAY FOCUSING

Moore's law adapted to the X-ray world:

ESRF Red Book (1987): very few beamline projects aiming even for 10 micron sized beams

Now optics exist for 10nm beams

Routine application of submicron beams still complicated

Also many engineering issues in implementing stable, reliable X-ray nanofocusing systems



Historical evolution of the measured spot size for different hard x-ray focusing elements *(courtesy C. Morawe)*

- H. Mimura et al. Nature Physics, 6, 122-125 (2010).
- J. Vila-Comamala et al., Ultramicroscopy,**109**,1360–1364 (2009)
- H. Kang et al., Physical Review Letters, 96:127401 (2006)
- C. Schroer et al., Physical Review Letters, 94:054802 (2005)



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ESRF

HIGHLY SPECIALIZED EXPERIMENTAL STATIONS

adapted to one or more techniques...

- X-ray Diffraction & Scattering
- X-ray Spectroscopy
- X-ray Fluorescence
- X-ray Imaging ...
- ... on samples of varying types
- Inorganic/organic crystals
- Colloidal solutions
- Fossils
- Cells
- Industrial materials ...

... and different sample environments





X-RAY DIFFRACTOMETER





HARD (5-70KEV) X-RAY MICROPROBE (ESRF-ID22)





HIGH THROUGHPUT CRYSTALLOGRAPHY



AUTOMATION AND HIGH THROUGHPUT









SAMPLE ENVIRONMENT

Particularly for:

- High temperature (furnaces)
- Low temperature (cryostat)
- Magnetic field
- Electric field
- Pressure application
- Controlled gas atmospheres
- Pump-probe experiments

Also to limit sample damage due to photon absorption (e.g. protein crystallography experiments) ...

Mini flow cryostat: 2 Kelvin



Induction furnace 3000 °C

Courtesy: Peter van der Linden



MINI PULSED MAGNETIC FIELD

High duty cycle minicoil

• monolithic



• slit coil



cooling surface





EXTREME CONDITIONS (T, P)





Diamond Anvil Cell (DAC)

1 million atmospheres (Bars) =100 Billion Pascals (GPa))

Record Pressure: 650 GPa L. Dubrovinsky et al., Nature Commun. 3, 1163, 2012.

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Courtesy M. Mezouar (ESRF-ID27)



EXTREME CONDITIONS (T, P)



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Courtesy M. Mezouar (ESRF-ID27)



EXTREME CONDITIONS (T, P)



Courtesy M. Mezouar (ESRF-ID27)



EXTREME CONDITIONS (T, P) – ESRF - ID27



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Courtesy M. Mezouar (ESRF-ID27)



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X-RAY DETECTORS

Measure X-ray intensity (sometimes energy too) – selection depends upon various factors e.g.

- 0-D, 1-D, 2-D
- Spatial, energy resolution
- Efficiency (Energy), dynamic range
- Signal intensity: photon counting, integrating max count rate
- Robustness
- Price

Earliest detector: Film – still used

Direct conversion

• Absorbed X-rays directly generate electrical signal e.g. photodiodes, pixel-detectors, silicon drift-diodes

Indirect conversion

• X-rays absorbed by a conversion medium and secondary signal such as light, heat detected e.g. scintillator PMT, optically coupled CCD, bolometer, calorimeter



ELASTIC SCATTERING: DIFFRACTION, SMALL ANGLE SCATTERING...

 Scattered photons conserve their initial energy, i.e. only momentum changed angular measurements are required, usually measured with 2D spatially resolving detectors

 \Rightarrow angular resolution can be varied by changing detector-sample distance

- Large dynamic range may be required (crystal diffraction can cover ~8 orders of magnitude!)
 - detectors used:

 scintillator-PMT; silicon-diode, -APD using diffractometer
 solid state semiconductors (1D strip, 2D area PADs)
 'indirect detection' with flat panel a-Si or CMOS readout
 2D area scintillator-optic-CCD cameras
 (laser read-out phosphor image plates, MWPC gas detectors)





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Courtesy: John Morse





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'INDIRECT' X-RAY DETECTION: CCD CAMERA SYSTEMS

position-resolved 2D area detectors, especially high resolution X-ray imaging



for detector areas above ~1cm², fibre optic gives more efficient optical coupling to CCD

Courtesy: John Morse



HIGH RESOLUTION CRYSTAL SCREEN-LENS-CCD SYSTEMS



2D X-RAY DETECTORS

Roentgen: "... Photographic plates and film are "susceptible to x-rays", providing a valuable means of recording the effects..."















CHRONOLOGICAL EVOLUTION OF FAST IMAGING (ESRF)

Orange points: spatial resolution 1-2µm





Data courtesy: M. Di Michiel ID15-ESRF



EVOLUTION OF FAST HARD X-RAY IMAGING

FROM 100 FRAMES/1h TO 100FRAMES/2ms



Challenge: Data processing and storage: 3000Gb / Day



CONCLUSIONS

- Present day synchrotron radiation sources offer a unique tool for probing the interior of matter over length scales ranging from the few cm to sub-atomic dimensions
- The full potential of the continually improving sources can only be exploited by parallel developments in appropriate X-ray instrumentation
 - X-ray optics/ optomechanics
 - Sample alignment systems
 - Sample environments
 - X-ray Detectors
- The new capabilities of instrumentation in these fields mean that increasingly sample throughput is limited by:
 - Sample exchange
 - Evaluation of data quality
 - Instrument control (optimised data collection)
 - Data handling and archiving
- ESRF Phase II Upgrade will include an ambitious instrumentation development program addressing many of these issues



THANK YOU

